Special Issue

Non-destructive Testing by Ultrasounds

Message from the Guest Editors

This Special Issue (SI) encourages researchers to present new scientific achievements related to non-destructive testing by ultrasounds, namely new theories and application methods. Ultrasound is an important technique in NDT being largely used in industry. Metal and composite materials used in critical applications, such as aerospace structures, require appropriate NDT to guarantee safety. Thus, contributions on the latest R&D achievements on ‘Non-Destructive Testing by Ultrasounds’, methodologies of testing, and evaluation, as well as on the development of new equipment, analyses, and approaches to non-destructive measurements are welcome. Authors are encouraged to submit contributions in any of the following or related areas for NDT by ultrasounds:

- Ultrasonic non-destructive testing / ultrasonic non-destructive evaluation;
- Ultrasonic-based structural health monitoring and damage detection;
- Material characterization;
- NDT of composites
- Ultrasound phased arrays;
- Guided waves.

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Deadline for manuscript submissions

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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